

**LIST 12 (See S.No. 187 of the Table)**

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|---|--|---|
| (1) LSI / VLSI tester   | (14) Lithography systems   | (26) Wafer sawing machine;<br>Wafer prober                                      |
| (2) Micromanipulators   | (15) Direct step on wafers /<br>steppers   | (27) Leak detection system  |
| (3) Molecular beam epitaxy<br>system (MBE system)   | (16) X-ray lithography systems   | (28) Clean room air showers   |
| (4) Epitaxial reactors  | (17) E-Beam mask making<br>system  | (29) Particle monitor / counter<br>both air and liquid borne                    |
| (5) Chemical vapour deposition<br>(CVD) system - Low pressure<br>CVD (LP CVD) - Metal organic<br>CVD (MO CVD) | (18) E-Beam direct write system  | (30) Automatic encapsulation<br>system; Automatic marking /<br>branding machine |
| (6) High pressure oxidation<br>systems  | (19) Mask aligners   | (31) Clean room laminar flow air<br>handling system                             |
| (7) Chemical etching systems  | (20) Mask inspection systems<br>(comparators)  | (32) Ultra clean room equipment   |
| (8) Plasma etchers  | (21) Tape automated bonders  | (33) Ultra high purity<br>demineralised water treatment<br>plant                |
| (9) Reactive ion beam etchers<br>(RIBE)   | (22) Laser zappers   | (34) PVDF welding and orbital<br>welding machines                               |
| (10) Reactive ion etchers   | (23) Wafer recognition wire<br>bonders   | (35) Ultra high pure (UHP) gas<br>distribution system                           |
| (11) RF sputtering systems  | (24) Wafer scribe or Wafer<br>slicer or Wafer sawing machine<br>or Wafer fractures or any<br>combination thereof | (36) Toxic gas distribution /<br>monitoring system                              |
| (12) Direct digital control<br>furnaces   | (25) Die bonders or wire bonders<br>or combination thereof   |   |
| (13) Ion-implanters (low/ medium<br>/ high current)   |  |   |